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Comments on "optimizing error masking in BIST by output data modification"

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Abstract

In a recent paper [1] a scheme for reducing error masking probability by modifying the output data before compaction has been proposed. The aim of the present comment is to direct one's attention to another method of modifier construction. The method employs a linear combinational circuit (LCC) as modifier. Such an approach may require little extra hardware. Furthermore, there is an efficient algorithm for finding a modifier. © 1991 Kluwer Academic Publishers.

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Keywords

Output data compaction, output data modification, Walsh coefficients